

Search Notes

Application/Control No.

10/691,804

Examiner

Shih-wen Hsieh

Applicant(s)/Patent under
Reexamination

HASHI ET AL.

Art Unit

2861

SEARCHED

Class	Subclass	Date	Examiner
347	22,24,29 30,32,33 35	2/14/2005	<i>SWH</i> SWH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR